



### P-Channel 100-V (D-S) MOSFET

#### CHARACTERISTICS

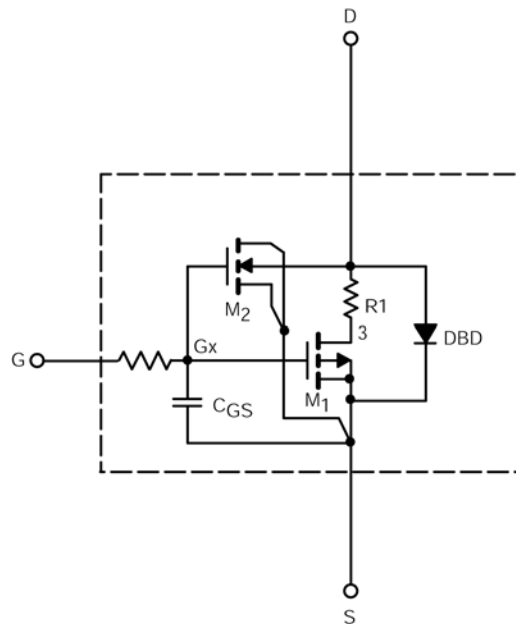
- P-Channel Vertical DMOS
- Macro Model (Subcircuit Model)
- Level 3 MOS
- Apply for both Linear and Switching Application
- Accurate over the -55 to 125°C Temperature Range
- Model the Gate Charge, Transient, and Diode Reverse Recovery Characteristics

#### DESCRIPTION

The attached spice model describes the typical electrical characteristics of the p-channel vertical DMOS. The subcircuit model is extracted and optimized over the -55 to 125°C temperature ranges under the pulsed 0-V to 10-V gate drive. The saturated output impedance is best fit at the gate bias near the threshold voltage.

A novel gate-to-drain feedback capacitance network is used to model the gate charge characteristics while avoiding convergence difficulties of the switched  $C_{gd}$  model. All model parameter values are optimized to provide a best fit to the measured electrical data and are not intended as an exact physical interpretation of the device.

#### SUBCIRCUIT MODEL SCHEMATIC



This document is intended as a SPICE modeling guideline and does not constitute a commercial product data sheet. Designers should refer to the appropriate data sheet of the same number for guaranteed specification limits.



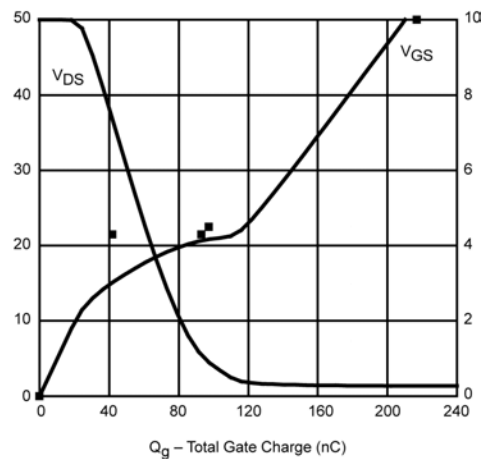
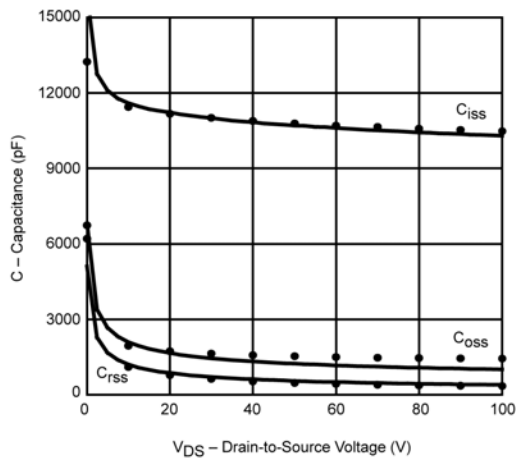
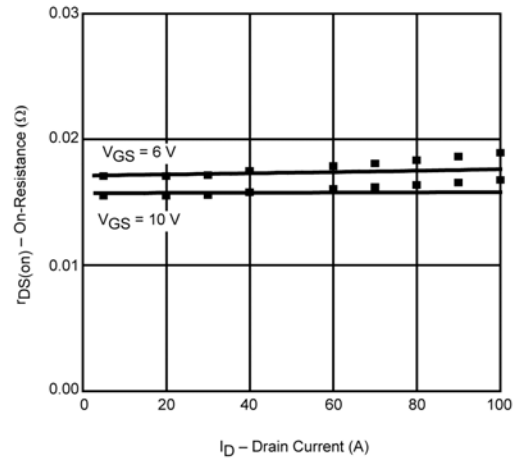
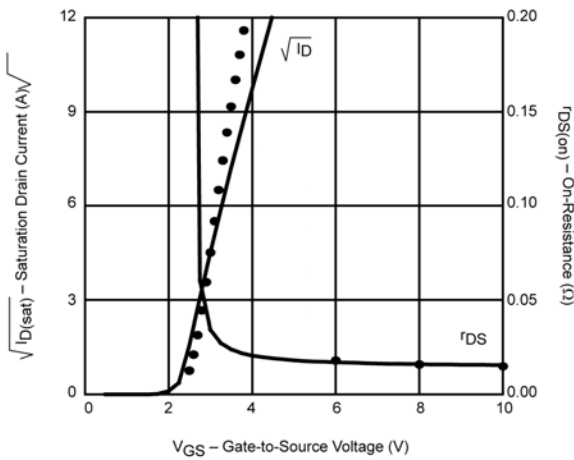
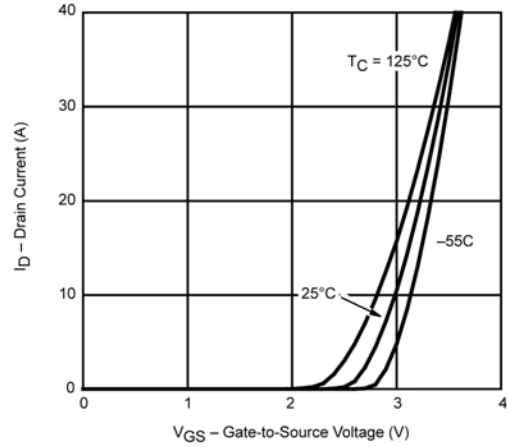
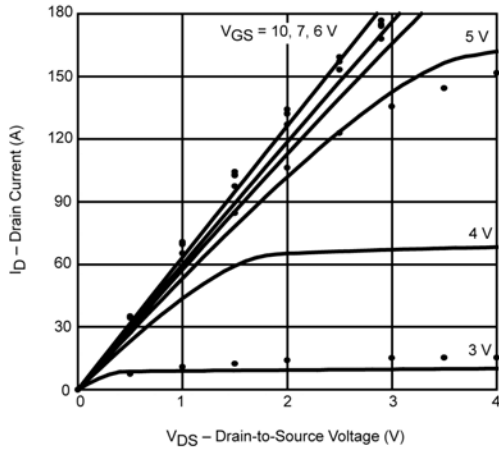
SPECIFICATIONS (T <sub>J</sub> = 25°C UNLESS OTHERWISE NOTED)					
Parameter	Symbol	Test Condition	Simulated Data	Measured Data	Unit
<b>Static</b>					
Gate Threshold Voltage	V <sub>GS(th)</sub>	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = -250 μA	1.9		V
On-State Drain Current <sup>a</sup>	I <sub>D(on)</sub>	V <sub>DS</sub> = -5 V, V <sub>GS</sub> = -10 V	313		A
Drain-Source On-State Resistance <sup>a</sup>	r <sub>DS(on)</sub>	V <sub>GS</sub> = -10 V, I <sub>D</sub> = -20 A	0.0157	0.0156	Ω
		V <sub>GS</sub> = -4.5 V, I <sub>D</sub> = -15 A		0.0173	
Forward Voltage <sup>a</sup>	V <sub>SD</sub>	V <sub>DS</sub> = -15 V, I <sub>F</sub> = -20 A	0.88	0.80	V
<b>Dynamic<sup>b</sup></b>					
Input Capacitance	C <sub>iss</sub>	V <sub>DS</sub> = -50 V, V <sub>GS</sub> = 0 V, f = 1 MHz	10710	11100	pF
Output Capacitance	C <sub>oss</sub>		556	700	
Reverse Transfer Capacitance	C <sub>rss</sub>		1214	1690	
Total Gate Charge <sup>c</sup>	Q <sub>g</sub>	V <sub>DS</sub> = -50 V, V <sub>GS</sub> = -10 V, I <sub>D</sub> = -90 A		217	nC
Gate-Source Charge <sup>c</sup>	Q <sub>gs</sub>	V <sub>DS</sub> = -50 V, V <sub>GS</sub> = -4.5 V, I <sub>D</sub> = -90 A	117	97	
Gate-Drain Charge <sup>c</sup>	Q <sub>gd</sub>		42	42	
			51	51	

Notes

- a. Pulse test; pulse width ≤ 300 μs, duty cycle ≤ 2%.
- b. Guaranteed by design, not subject to production testing.
- c. Independent of operating temperature.



COMPARISON OF MODEL WITH MEASURED DATA (T<sub>J</sub>=25°C UNLESS OTHERWISE NOTED)



Note: Dots and squares represent measured data.